

<u>HS96</u>	<u>Description</u>	<u>Base rate</u>	<u>Bound rate</u>	<u>Implementation</u>	<u>Present concession established</u>	<u>Concession first incorporated in a GATT Schedule</u>	<u>Earlier INRs</u>	<u>ODCs</u>
90262092	----Oil pressure meters for motor vehicles, NS in subheading No.2091	6.0%	0	2000			0	0
90262099	----Other	12.0%	0	2000			0	0
902680	-Other instruments or apparatus				WT/Let			
90268010	---Operating on basis of electric phenomenon modified according to the object inspected	8.0%	0	2000			0	0
90268091	----Specially made for motor vehicle, excluding tractors, forklifts, rail-mounted vehicle or armoured combat vehicle	6.0%	0	2000			0	0
90268099	----Other	6.0%	0	2000			0	0
902690	-Parts and accessories							
90269010	---For apparatus operating on the basis of electric phenomenon modified according to the object inspected	2.0%	0	2000			0	0
90269091	----Specially made for motor vehicles, excluding tractors, forklifts and concrete mixers, rail-mounted vehicle or armoured combat vehicle and excluding those specially made for apparatus specified in subheading No. 2099	6.0%	0	2000			0	0
90269099	----Other	6.0%	0	2000			0	0
9027	Instruments and apparatus for physical or chemical analysis (for example, polarimeters, refractometers, spectrometers, gas or smoke analysis apparatus); instruments and apparatus for measuring or checking viscosity, porosity, expansion, surface tension or				WT/Let			
90272000	-Chromatographs and electrophoresis instruments	5.6%	0	2000			0	0

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902730	-Spectrometers, spectrophotometers and spectrographs using optical radiations (UV, visible, IR)								
90273010	---Operating on basis of electric phenomenon modified according to the object inspected	0.0%	0	1997				0	
90273090	---Other	5.6%	0	2000				0	
902750	-Other instruments and apparatus using optical radiations (UV, visible, IR)								
90275011	----Photo fluorometer; apparatus for automatic measuring, checking or analysis of human body liquids	0.0%	0	1997				0	
90275012	----Sensitometers and densitometers	0.0%	0	1997				0	
90275013	----Light meters for photography or cinematography	12.0%	0	2000				0	
90275019	----Other	5.6%	0	2000				0	
90275091	----Refractometers for manual use or immersion	12.0%	0	2000				0	
90275099	----Other	5.6%	0	2000				0	
902780	-Other instruments and apparatus								
90278010	---Blood gas analysers	0.0%	0	1997				0	
90278020	---Apparatus for automatically measuring, checking or analysing human body liquids	0.0%	0	1997				0	
90278030	---Sensitometers and densitometers	0.0%	0	1997				0	
90278040	---pH meters	12.0%	0	2000				0	
90278090	---Other	5.6%	0	2000				0	
ex902790	-Microtomes; parts and accessories								
902790	--Parts and accessories of products of heading 9027, other than for gas or smoke analysis apparatus and microtomes								
ex90279090	--Parts and accessories of products of heading 9027, other than for gas or smoke analysis apparatus and microtomes	5.6%	0	2000				0	

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9030	Oscilloscopes, spectrum analysers and other instruments and apparatus for measuring or checking electrical quantities, excluding meters of heading No. 90.28; instruments and apparatus for measuring or detecting alpha, beta, gamma, X-ray, cosmic or other i				WT/Let			
90304000	-Other instruments and apparatus, specially designed for telecommunications (for example, cross-talk meters, gain measuring instruments, distortion factor meters, psophometers)	2.0%	0	2000			0	
90308200	-Other instruments and apparatus: --For measuring or checking semiconductor wafers or devices	2.0%	0	2000	WT/Let		0	
ex903090	-Parts and accessories				WT/Let			
ex903090	--Parts and accessories; of instruments and apparatus for measuring or checking semiconductor wafers or devices				WT/Let			
903090	--Parts of instruments and appliances for measuring or checking semiconductor wafers or devices							
ex90309090	--Parts of instruments and appliances for measuring or checking semiconductor wafers or devices	2.0%	0	2000			0	
9031	Measuring or checking instruments, appliances and machines, not specified or included elsewhere in this Chapter; profile projectors.							
	-Other optical instruments and appliances:				WT/Let			

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90314100	--For inspecting semiconductor wafers or devices or for inspecting photomasks or reticles used in manufacturing semiconductor devices	0.0%	0	1997				0
ex903149	--Other				WT/Let			
903149	---Optical instruments and appliances for measuring surface particulate contamination on semiconductor wafers							
ex90314920	---Optical instruments and appliances for measuring surface particulate contamination on semiconductor wafers	0.0%	0	1997				0
ex90314990	---Optical instruments and appliances for measuring surface particulate contamination on semiconductor wafers	6.0%	0	2000				0
ex903190	-Parts and accessories				WT/Let			
ex903190	--Parts and accessories of optical instruments and appliances for inspecting semiconductor wafers or devices or for inspecting masks, photomasks or reticles used in manufacturing semiconductor devices				WT/Let			
903190	--Parts and accessories of optical instruments and appliances for measuring surface particulate contamination on semiconductor wafers							
ex90319010	--Parts and accessories of optical instruments and appliances for measuring surface particulate contamination on semiconductor wafers	2.0%	0	2000				0

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ex90319030	--Parts and accessories;of optical instruments and appliances for measuring surface particulate contamination on semiconductor wafers	0.0%	0	1997			0	0
ex90319090	--Parts and accessories of optical instruments and appliances for measuring surface particulate contamination on semiconductor wafers	12.0%	0	2000			0	0

**Israel**

26 March 1997

With respect to any product described in or for Attachment B to the Annex to the Ministerial Declaration on Trade in Information Technology Products (WT/MIN(96)/16), to the extent not specifically provided for in this Schedule, the customs duties on such product, as well as any other duties and charges of any kind (within the meaning of Article II:1(b) of the General Agreement on Tariffs and Trade 1994), shall be bound and eliminated, as set forth in paragraph 2(a) of the Annex to the Declaration, wherever the product is classified.

**Description****HS**

Quartz reactor tubes and holders designed for insertion into diffusion and oxidation furnaces for production of semiconductor wafers	70200099
Chemical vapor deposition apparatus for semiconductor production	84198991, 84198999
Parts of chemical vapor deposition apparatus for semiconductor production	84199090
Apparatus for stripping or cleaning semiconductor wafers	84569900
Laser cutters for cutting contacting tracks in semiconductor production by laser beam	84561000
Machines for sawing monocrystal semiconductor boules into slices, or wafers into chip	84641010, 84641090
Parts of machines for sawing monocrystal semiconductor boules into slices, or wafers into chips	84669110, 84669190
Parts of dicing machines for scribing or scoring semiconductor wafers	84669110, 84669190
Parts of laser cutters for cutting contacting tracks in semiconductor production by laser beam	84669310, 84669320, 84669390
Parts of apparatus for stripping or cleaning semiconductor wafers	84669310, 84669320, 84669390
Encapsulation equipment for assembly of semiconductors	84771000
Parts of encapsulation equipment	84779000
Automated machines for transport, handling and storage of semiconductor wafers, wafer cassettes, wafer boxes and other material for semiconductor devices	84283990
Apparatus for physical deposition by sputtering on semiconductor wafers	84198910, 85438990
Apparatus for wet etching, developing, stripping or cleaning semiconductor wafers and flat panel displays	84798991, 84988999, 84798991, 84798999
Die attach apparatus, tape automated bonders, and wire bonders for assembly of semiconductors	84798991, 84798999, 85158010, 85159090
Encapsulation equipment for assembly of semiconductors	84798991, 84798999, 85438990
Machines for bending, folding and straightening semiconductor leads	84622191, 84622199, 84622990